

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-2356priority SERIAL NO.
10/364,054LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Luan C. Tranpriority FILING DATE
February 10, 2003priority GROUP
2812

10/624628

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QU	AA	6,458,666 B2	10-2002	Wasshuber			
QU	AB	6,444,548 B2	09-2002	Divakaruni et al.			
QU	AC	3,886,003	05-1975	Takagi et al.			
QU	AD	4,366,338	12-1982	Turner et al.			
QU	AE	6,008,115	12-1999	Jung			
QU	AF	6,506,647 B2	01-2003	Kuroda et al.			
QU	AG	US2001/0036713A1	11-01-2001	Rodder et al.			July 5, 2001
QU	AH	US2002/0034865A1	03-21-2002	Uimimoto et al.			Nov. 30, 2001
QU	AI	09/876,722		Scott			June 6, 2001
QU	AJ	10/133,193		McQueen et al.			April 26, 2002
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

QU	AQ	Young et al., "A 0.13 μ m CMOS Technology with 193 nm Lithography and Cu/Low-k for High Performance Applications", IEDM, pgs. 563-566, April 2000.
QU	AR	Yeh et al., "Optimum Halo Structure for Sub-0.1 μ m CMOSFETs", IEEE Transactions on Electronic Devices, Vol. 48, No. 10, October 2001, pgs. 2357-2362.
QU	AS	Bouillon et al., "Re-examination of Indium implantation for a low power 0.1 μ m technology", IDEM, pgs. 897-900, 1995 (year is sufficient so that date is not in issue).

EXAMINER

DATE CONSIDERED

James M. Kennedy Feb. 15, 2005

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1/3 IDS 11/13/03

Form PTO-140

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
MI22-2356

SERIAL NO.
10/624,628

APPLICANT
Luan C. Tran

FILING DATE
July 21, 2003

GROUP
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PATENT & TRADEMARK OFFICE

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(Indicate several sheets if necessary)

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gu	AA 6,144,079 A	11-2000	Shirahata et al.			
gu	AB 6,033,952	03-2000	Yasumura, et al.			
gu	AC 6,124,168	09-2000	Ong			
gu	AD 5,688,705	11-1997	Bergemont			
gu	AE 5,866,448	02-1999	Pradcep et al.			
gu	AF 5,858,847	01-1999	Zhou et al.			
gu	AG 6,380,598	04-2002	Chan			
gu	AH 6,060,364	05-2000	Maszara et al.			
gu	AI 6,194,276 B1	02-2001	Chan et al.			
gu	AJ 6,359,319 B1	03-2002	Noda			
gu	AK 5,164,806	11-1992	Nagatomo et al.			
gu	AL 4,937,756	06-1990	Hsu et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
gu	AM EP 0718881	06/96	EPO, Chan				
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

gu	AR	Watanabe, H. et al., <i>Novel 0.44μm² Ti-Salicide STI Cell Technology for High-Density NOR Flash Memories and High Performance Embedded Application</i> , IEEE 1998, pp. 36.2.1 - 36.2.4.
gu	AS	Wolf, S., <i>"Silicon Processing for the VLSI Era"</i> , Vol. 2, pp. 632-635.
gu	AT	MITSUBISHI ELECTRIC WEBSITE: Reprinted from website http://www.mitsubishielectric.com/r_and_d/tech_showcase/ts8.php on 3/29/2001: "8. Production Line Application of a Fine Hole Pattern-Formation Technology for Semiconductors", on 3/29/2001, 4 pgs

EXAMINER: *Geniv M. Kennedy* DATE CONSIDERED: *Feb 15, 2005*

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2/3 IDS 11/13/03

Form PTO-1019

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
M122-2356

SERIAL NO.
10/624,628

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OFFICE OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT
Luan C. Tran

FILING DATE
July 21, 2003

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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gm	AA 5,930,614	07-1999	Eimori et al.			
gm	AB 5,635,744	06-1997	Hidaka et al.			
gm	AC 6,204,536	03-2001	Maeda et al.			
gm	AD 6,515,899 B1	02-2003	Tu et al.			
gm	AE 4,570,331	02-1986	Eaton, Jr. et al.			
gm	AF 6,429,079 B1	08-2002	Maeda et al.			
gm	AG 6,607,979 B1	08-2003	Kamiyama			
gm	AH 4,686,000	08-1987	Heath			
gm	AI 5,814,875	09-1998	Kumazaki			
gm	AJ 5,654,573	08-1997	Oashi et al.			
gm	AK 6,479,330 B2	11-2002	Iwamatsu et al.			
gm	AL 6,586,803	07-2003	Hidaka et al.			

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Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)


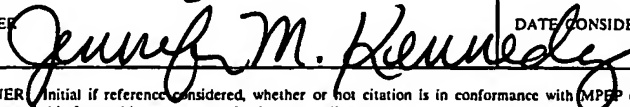
gm	AR	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/sep99/docs/feature1.asp on 3/29/2001: "Resists Join the Sub-A Revolution", 9 pgs.
gm	AS	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/aug99/docs/lithography.asp on 3/29/2001: "Paths to Smaller Features", 1 pg.
al	AT	Wolf, S., "Silicon Processing for the VLSI Era, Vol. 1: Process Technology," Lattice Press 1986, pp. 434-437.

EXAMINER *James M. Kennedy* DATE CONSIDERED *Feb 15, 2005*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

3/3 IDS 11/13/03

Sheet 3 of 3

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2356		SERIAL NO. 10/624,628		
 <p>LIST OF ART CITED BY APPLICANT (Indicate several sheets if necessary)</p>				APPLICANT Luan C. Tran				
				FILING DATE July 21, 2003		GROUP 2812		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
gm	AA	6,352,401 B1	04-2003	Dennison				
gm	AB	6,627,524 B2	09-2003	Scott				
gm	AC	US2002/0182829A1	12-2002	Chen				
gm	AD	US2002/0164846A1	11-2002	Lin et al.			Apr. 19, 2002	
gm	AE	US2003/0071310A1	04-2003	Salling et al.			Oct. 11, 2001	
	AF							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
gm	AR		"Session 18: Integrated Circuits and Manufacturing - DRAM and Embedded DRAM Technology," 2001 IEDM Technical Program, 2001 IEEE International Electron Devices Meeting, Dec. 4, 2001, reprinted 11/15/01 from http://www.his.com/~iedm/techprogram/sessions/s18.html , pp. 1-2.					
	AS							
	AT							
EXAMINER					DATE CONSIDERED			Feb. 15, 2005
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4/1 IDS

MAR-11-2004 13:15

WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-2356		SERIAL NO. 10/024,628	
LIST OF ART CITED BY APPLICANT (Use reverse sheets if necessary)				APPLICANT Lina C. Tran			
				FILING DATE July 21, 2003		GROUP 2811	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
gu	AA	6,521,487 B1	02-2003	Chen et al.			
gu	AB	6,492,694 B2	12-2002	Nobbe et al.			
gu	AC	6,468,865 B1	10-2002	Yang et al.			
gu	AD	6,451,704 B1	09-2002	Pradeep et al.			
gu	AE	6,436,747 B1	08-2002	Segawa et al.			
gu	AF	6,362,034 B1	03-2002	Sanford et al.			
gu	AG	6,277,720 B1	08-2001	Doshi et al.			
gu	AH	5,923,973	07-1999	Roland			
gu	AI	5,854,934	02-1999	Kadoh et al.			
gu	AJ	6,180,406 H1	01-2001	Yu et al.			
gu	AK	6,207,510 B1	03-2001	Ancha et al.			
gu	AL	US2003/0030112A1	02-2003	Wada et al.			
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Document Number	Date	Country	Class	Subclass	Translation		
AM					Yes	No	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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gu		Feb 15, 2005					
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APR-16-2004 16:43

WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-2336SERIAL NO.
10524628LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Lam C. TsaiFILING DATE
July 21, 2003CLASS
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
SM	AA	5,841,185	11-1998	Ishikawa			
SM	AB	6,331,458 B1	12-2001	Anjum et al.			
SM	AC	6,251,744 B1	06-2001	Su et al.			
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EXAMINER

(DATE RECONSIDERED)

Jennifer M. Kennedy Feb. 15, 2005

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NOV-01-2004 16:09

WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M12-1156		SERIAL NO. 10824,629	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				FILING DATE July 21, 2003		GROUP 2811	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
CU	AA	5,767,337	06-1998	Kaziyali			
GU	AB	5,369,295	11-1994	Vimal			
GU	AC	5,397,900	03-1995	Murkhi			
GU	AD	5,493,728	04-1997	Hidaka			
GU	AE	5,672,526	09-1997	Kawamura			
GU	AF	5,223,704	07-1993	Wakemitsu et al.			
GU	AG	5,440,161	08-1995	Iwamatsu et al.			
GU	AH	5,353,012	10-1994	Yamaguchi et al.			
GU	AI	5,450,226	01-1999	Wu			
GU	AJ	5,877,056	03-1999	Wu			
GU	AK	6,516,113 B1	02-2003	Boyce-Edi			
GU	AL	6,642,591 B2	11-2003	Matsuda et al.			
GU	AM	6,297,082 B1	10-2001	Lin et al.			
GU	AN	US2002/0043672A1	04-2002	Maeda et al.			
GU	AO	US2003/0169231	10-2003	Clevenger et al.			
FOREIGN PATENT DOCUMENTS							
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EXAMINER Jennifer M. Kennedy							
DATE CONSIDERED Feb. 15, 2005							
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